

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1957	716/4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:46
L2	579	716/4.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:47
L3	13	716/4.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware) and "hardware resources"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51
L4	17	714/25.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware) and "hardware resources"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:52
L5	3	714/27.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware) and "hardware resources"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51
L6	2	714/31.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware) and "hardware resources"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51
L7	273	714/31.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51
L8	1663	714/25.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51
L9	184	714/27.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:51

L10	17	714/25.ccls. and (rio or programmable or configurable or reconfigur\$4 or firmware) and "hardware resources"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 08:52
S3	872	DEBUG\$4 NEAR5 ((INTEGRATED ADJ CIRCUIT) OR IC)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 13:32
S4	34435	(DEBUG\$4 OR TEST\$3) NEAR5 ((INTEGRATED ADJ CIRCUIT) OR IC)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:15
S5	222	"design data base"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S6	1323	"design database"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S7	3	"design data-base"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S8	3	"design data-base" and (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S9	99	"design data base" and (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S10	3	"design data-base" and (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16
S11	731	"design database" and (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:16

S12	466	(S9 or S10 or S11) and (pattern or template or framework)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:17
S13	405	(S9 or S10 or S11) and (pattern or template or framework) and (test\$3 or debug\$4 or simulat\$3 or emulat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 11:18
S14	439	(S9 or S10 or S11) and (pattern or template or framework) and (test\$3 or debug\$4 or simulat\$3 or emulat\$3) and (result or output or log or datalog or report)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:21
S15	146	(S9 or S10 or S11) and (pattern or template or framework) and (test\$3 or debug\$4 or simulat\$3 or emulat\$3) and (result or output or log or datalog or report) and (feedback or reformat\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:19
S16	53	(S9 or S10 or S11) and (pattern or template or framework) and (test\$3 or debug\$4 or simulat\$3 or emulat\$3) and (result or output or log or datalog or report) and (feedback or reformat\$4) and (detect\$3 or identify\$3 or identification) near3 (fault\$3 or fail\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:20
S17	105	(S9 or S10 or S11) and (pattern or template or framework) and (test\$3 or debug\$4 or simulat\$3 or emulat\$3) near5 pin) and (result or output or log or datalog or report)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:27
S18	26	S15 and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:23
S19	322057	(creat\$3 or generat\$3) near5 (design or signal or code or pattern or stimul\$2 or pulse or format) near5 (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:26
S20	238461	(creat\$3 or generat\$3) near3 (design or signal or code or pattern or stimul\$2 or pulse or format) near3 (circuit or ic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:26

S21	71	S20 and (S15 or S16 or S17)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 11:27
S22	20	DEBUG\$4 NEAR5 ((INTEGRATED ADJ CIRCUIT) OR IC) same (adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 14:46
S23	0	("6282676").URPN.	USPAT	OR	OFF	2005/03/17 14:45
S24	3	("4928278" "5319224" "5432797").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/17 14:45
S25	0	DEBUG\$4 NEAR5 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test or pattern or format or design) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 14:48
S26	10	DEBUG\$4 NEAR5 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 14:49
S27	371	(DEBUG\$4 or test\$3 or analyze or analysis) NEAR5 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 14:50
S28	300	(DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/17 14:51

S29	379	(DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 14:51
S30	4	("6327686").URPN.	USPAT	OR	OFF	2005/03/17 15:39
S31	1	("4646299").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/17 15:58
S32	0	(test\$3 or debug\$4) same (circuit or ic) and "failure indicat\$3"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 17:54
S33	183	(test\$3 or debug\$4) same (circuit or ic) and "failure indicator"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 17:55
S34	430	(test\$3 or debug\$4) same (circuit or ic) and "failure indication"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 17:55
S35	84	(test\$3 or debug\$4) same (circuit or ic) and "failure indication" same (chang\$3 or alter\$5 or modify\$3 or modification or reformat\$4 or chang\$3 or correct\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 17:57
S36	82	(test\$3 or debug\$4) same (circuit or ic) and "failure indication" same (chang\$3 or alter\$5 or modify\$3 or modification or reformat\$4 or chang\$3 or correct\$3) and (generat\$3 or form\$3 or creat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 18:02
S37	3	(test\$3 or debug\$4) same (circuit or ic) and "failure indication" same (chang\$3 or alter\$5 or modify\$3 or modification or reformat\$4 or chang\$3 or correct\$3) and (generat\$3 or form\$3 or creat\$3) and ("design pattern" or "debug file" or "design database" or "design data base" or "design data-base" or "pattern format")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 17:58

S38	42734	((test\$3 or debug\$4) and (circuit or ic)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 18:02
S39	0	"debug an integrated circuit".ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 18:02
S40	62	(debug and "integrated circuit").ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 18:03
S41	486	717/124.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:05
S42	285	717/131.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:04
S43	1114	714/726.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:04
S44	2732	714/718.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:04
S45	1198	714/738.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:04
S46	0	717/124.ccls. and (DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:05

S47	0	717/131.ccls. and (DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:05
S48	3	714/726.ccls. and (DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:05
S49	13	714/718.ccls. and (DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:06
S50	17	714/738.ccls. and (DEBUG\$4 or test\$3 or analyze or analysis) NEAR3 (CIRCUIT OR IC) same (chang\$3 adapt\$3 or correct\$3 or feedback or modify\$3 or modification or recharacterization) near3 (test\$3 or pattern or format or design or debug\$4) near5 (fault\$3 or error or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/19 15:06
S51	96	"design pattern" and ("test pattern" or "tester pattern")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 13:34
S52	96	"design pattern" and ("test pattern" or "tester pattern")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 13:34
S53	96	"design pattern" and ("test pattern" or "tester pattern") and (debug\$4 or test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 13:46

S54	41	"design pattern" and ("test pattern" or "tester pattern") and (results or output or log\$4) and (format\$4 or reformat\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:07
S55	31	("4744047").URPN.	USPAT	OR	OFF	2005/10/19 13:59
S56	4	"design pattern" and ("test pattern" or "tester pattern") and (map\$4 near3 results)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:08
S57	0	"design pattern" and ("test pattern" or "tester pattern") and (map\$4 near3 design)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:09
S58	3	(design and test) near3 (" integrated circuit" or ic or asic) and ((map\$4 near3 (result or output)) near3 design)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:19
S59	1948	716/4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:27
S60	580	716/4.ccls. and patterns	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:27
S61	13	716/4.ccls. and patterns and reformat\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 14:27
S62	24	(design and test) near3 (" integrated circuit" or ic or asic) and (((map\$4 or transform\$3 or transl\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 design)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:29
S63	0	(design and test) and (((map\$4 or transform\$3 or transl\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 "design ptttern")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:20

S64	37	(design\$3 and test\$3) near3 ("integrated circuit" or ic or asic) and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 (design or hdl or vhdl))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 16:12
S65	13	S64 not S62	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:30
S66	0	"pattern format" near5 "design patern"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:59
S67	0	(modify or modification) near3 "pattern format"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:59
S68	4	"pattern format" near5 "design pattern"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 15:59
S69	41	(design\$3 and test\$3) near3 ("integrated circuit" or ic or asic) and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 (source or pattern or design or hdl or vhdl))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 16:10
S70	41	((design\$3 and test\$3) near3 pattern) and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 (source or pattern or design or hdl or vhdl))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 16:10
S71	3	717/124.ccls. and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or asociat\$3) near3 (result or output)) near3 (source or pattern or design or hdl or vhdl))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:51
S72	22	S70 not S64	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/19 16:12

S73	25557	((map\$4 or transform\$3 or translats\$3 or relat\$3 or associats\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translats\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:54
S74	204	717/???.ccls. and ((map\$4 or transform\$3 or translats\$3 or relat\$3 or associats\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translats\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:54
S75	253	717/???.ccls. and ((map\$4 or transform\$3 or translats\$3 or relat\$3 or associats\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translats\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 13:54
S76	230	717/???.ccls. and ((map\$4 or transform\$3 or translats\$3 or relat\$3 or associats\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translats\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl) and (develop\$4 or debug\$4 or test\$3 or design\$3 or ide)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 13:55
S77	244	717/???.ccls. and ((map\$4 or transform\$3 or translats\$3 or relat\$3 or associats\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translats\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl) and (develop\$4 or debug\$4 or test\$3 or design\$3 or ide)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:15

S78	177	717/???..ccls. and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or associat\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl) and (develop\$4 or debug\$4 or test\$3 or design\$3 or ide) and (hardware or firmware or ic or circuit or asic or smart or fpga or eeprom or eeprom)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 13:57
S79	12	("5185867").URPN.	USPAT	OR	OFF	2005/10/20 14:01
S80	23	717/???..ccls. and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or associat\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl) and (develop\$4 or debug\$4 or test\$3 or design\$3 or ide) and (chang\$3 or modify\$3 or modification or edit\$4) near3 design	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:16
S81	1	717/???..ccls. and ((map\$4 or transform\$3 or translat\$3 or relat\$3 or associat\$3 or relat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (result or output)) near5 (original or source or pattern or design or hdl or vhdl) and (develop\$4 or debug\$4 or test\$3 or design\$3 or ide) and (ide or cad) and "design pattern"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:16
S82	16892	((input near5 output) near5 ("clock signal")) or ("stimulus-response" or "stimulus response") or (vcd or "value change dump")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 11:38
S83	14733	((input near5 output) near5 ("clock signal")) or ("stimulus-response" or "stimulus response") or (vcd or "value change dump") and fail\$3 near3 "logic values"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 11:39

S84	14733	((input near5 output) near5 ("clock signal")) or ("stimulus-response" or "stimulus response") or (vcd or "value change dump") and fail\$3 near3 "logic values" and (map\$4 or relat\$3 or associat\$3 or interleav\$3 or transform\$3 or translat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (fault\$3 or fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 11:41
S85	18102	((input near5 output) near5 ("clock signal")) or ("stimulus-response" or "stimulus response") or (vcd or "value change dump") and fail\$3 near3 "logic values" and (map\$4 or relat\$3 or associat\$3 or interleav\$3 or transform\$3 or translat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (fault\$3 or fail\$3) and "signal patterns"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:41
S86	9026	((input near3 output) near3 ("clock signal")) or ("stimulus-response" or "stimulus response") or (vcd or "value change dump") same ((fail\$3 or fault\$3) near3 "logic values") and (map\$4 or relat\$3 or associat\$3 or interleav\$3 or transform\$3 or translat\$3 or referenc\$3 or refer\$4 or convert\$3 or transform or translat\$3) near3 (fault\$3 or fail\$3) near5 "signal patterns"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:43
S87	74950	signal near5 (fail\$3 or fault\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:44
S88	25192	(signal near3 (input or in)) same (signal near3 (output or out)) same (signal near3 (fail\$3 or fault\$3 or error))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:45
S89	477	S86 and S88	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:46

S90	41	S86 and S88 and data near3 pin	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/26 11:46
S91	605	717/124.CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 15:38
S92	1	717/124.CCLS. and stimul\$2 near3 ("integrated circuit" or ic or circuit) and (test\$3 or debug\$4) and (response or result or output)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 15:40
S93	1	717/124.CCLS. and stimul\$2 near3 ("integrated circuit" or ic or circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 15:40
S94	17	717/124.CCLS. and (stimul\$2 or signal\$4) near3 ("integrated circuit" or ic or circuit)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 15:41